

<b>Notice of References Cited</b>	Application/Control No. 10/754,200	Applicant(s)/Patent Under Reexamination NGUYEN ET AL.	
	Examiner Hiep T. Nguyen	Art Unit 2187	Page 1 of 1

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*	B	US-6,907,504	06-2005	Burton et al.	711/162
*	C	US-6,728,833	04-2004	Pruett et al.	711/114
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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